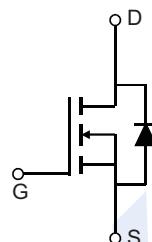
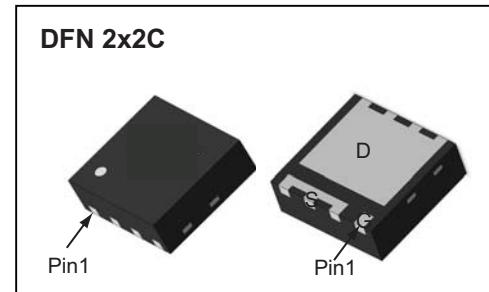


N-Channel MOSFET**AON2392 (KON2392)****■ Features**

- $V_{DS} = 100 \text{ V}$
- $I_D \text{ (at } V_{GS} = 10 \text{ V)} = 8 \text{ A}$
- $R_{DS(ON)} \text{ (at } V_{GS} = 10 \text{ V)} < 32 \text{ m}\Omega$
- $R_{DS(ON)} \text{ (at } V_{GS} = 4.5 \text{ V)} < 39 \text{ m}\Omega$

**■ Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise noted)**

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 20	
Continuous Drain Current	I_D	8	A
		6	
Pulsed Drain Current ^C	I_{DM}	32	
Power Dissipation ^B	P_D	4.1	W
		2.6	
Thermal Resistance.Junction- to-Ambient ^A	R_{thJA}	30	°C/W
Thermal Resistance.Junction- to-Ambient ^{AD}		55	
Junction Temperature	T_J	150	°C
Storage Temperature Range	T_{stg}	-55 to 150	

N-Channel MOSFET

AON2392 (KON2392)

■ Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$\text{Id} = 250 \mu\text{A}, \text{V}_{\text{GS}} = 0\text{V}$	100			V
Zero Gate Voltage Drain Current	I_{DSS}	$\text{V}_{\text{DS}} = 100 \text{ V}, \text{V}_{\text{GS}} = 0 \text{ V}$		1		μA
		$\text{V}_{\text{DS}} = 100 \text{ V}, \text{V}_{\text{GS}} = 0 \text{ V}, T_J = 55^\circ\text{C}$		5		
Gate to Source Leakage Current	I_{GSS}	$\text{V}_{\text{DS}} = 0 \text{ V}, \text{V}_{\text{GS}} = \pm 20 \text{ V}$			± 100	nA
Gate to Source Threshold Voltage	$\text{V}_{\text{GS(th)}}$	$\text{V}_{\text{DS}} = \text{V}_{\text{GS}}, \text{Id} = 250 \mu\text{A}$	1.4		2.4	V
Static Drain-Source On-Resistance	$\text{R}_{\text{DS(on)}}$	$\text{V}_{\text{GS}} = 10 \text{ V}, \text{Id} = 8 \text{ A}$			32	$\text{m}\Omega$
		$\text{V}_{\text{GS}} = 10 \text{ V}, \text{Id} = 8 \text{ A}, T_J = 125^\circ\text{C}$			57	
		$\text{V}_{\text{GS}} = 4.5 \text{ V}, \text{Id} = 6 \text{ A}$			39	
Forward Transconductance	g_{FS}	$\text{V}_{\text{DS}} = 5 \text{ V}, \text{Id} = 8 \text{ A}$		25		S
Input Capacitance	C_{iss}	$\text{V}_{\text{GS}} = 0 \text{ V}, \text{V}_{\text{DS}} = 50 \text{ V}, f = 1 \text{ MHz}$		840		pF
Output Capacitance	C_{oss}			64		
Reverse Transfer Capacitance	C_{rss}			4		
Gate Resistance	R_{g}	$\text{V}_{\text{GS}} = 0 \text{ V}, \text{V}_{\text{DS}} = 0 \text{ V}, f = 1 \text{ MHz}$		1.4		Ω
Total Gate Charge	$\text{Q}_{\text{g}}(10\text{V})$	$\text{V}_{\text{GS}} = 10 \text{ V}, \text{V}_{\text{DS}} = 50 \text{ V}, \text{Id} = 8 \text{ A}$		12.8	25	nC
Total Gate Charge	$\text{Q}_{\text{g}}(4.5\text{V})$			6.1	12	
Gate Source Charge	Q_{gs}			2.1		
Gate Drain Charge	Q_{gd}			1.8		
Output Charge	Q_{oss}	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=50\text{V}$		11		
Turn-On Delay Time	$\text{t}_{\text{d(on)}}$	$\text{V}_{\text{GS}} = 10 \text{ V}, \text{V}_{\text{DS}} = 50 \text{ V}, \text{R}_L = 5.85 \Omega, \text{R}_{\text{GEN}} = 3 \Omega$		7		ns
Turn-On Rise Time	t_{r}			8		
Turn-Off Delay Time	$\text{t}_{\text{d(off)}}$			24		
Turn-Off Fall Time	t_{f}			3		
Body Diode Reverse Recovery Time	trr	$\text{I}_{\text{F}} = 8 \text{ A}, \text{di/dt} = 500 \text{ A}/\mu\text{s}$		20		nC
Body Diode Reverse Recovery Charge	Q_{rr}			70		
Maximum Body-Diode Continuous Current	I_{s}				5	A
Diode Forward Voltage	V_{SD}	$\text{V}_{\text{GS}} = 0 \text{ V}, \text{I}_{\text{s}} = 1 \text{ A}$			1	V

Notes:

- A. The value of R_{eJA} is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.
- B. The power dissipation P_{D} is based on $T_{\text{J(MAX)}}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-case thermal resistance.
- C. Repetitive rating, pulse width limited by junction temperature $T_{\text{J(MAX)}}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_{\text{J}}=25^\circ\text{C}$
- D. The R_{eJA} is the sum of the thermal impedance from junction to lead R_{eJL} and case to ambient.
- E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.
- F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in^2 FR-4 board with 2oz Copper, assuming a maximum junction temperature of $T_{\text{J(MAX)}}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

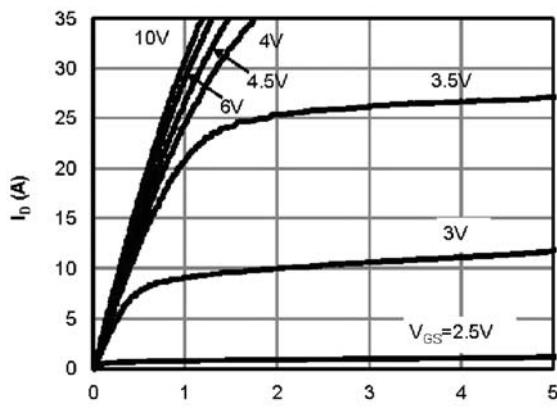
N-Channel MOSFET**AON2392 (KON2392)****■ Typical Electrical and Thermal Characteristics**

Figure 1: On-Region Characteristics (Note E)

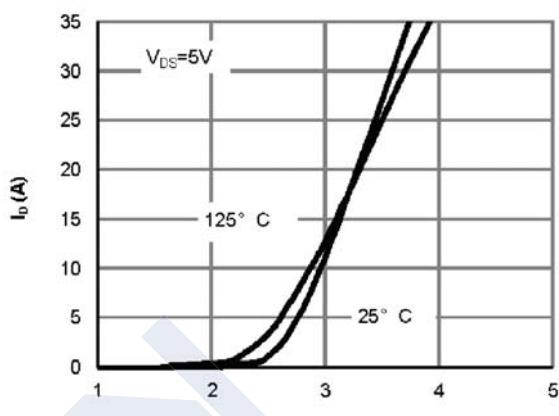


Figure 2: Transfer Characteristics (Note E)

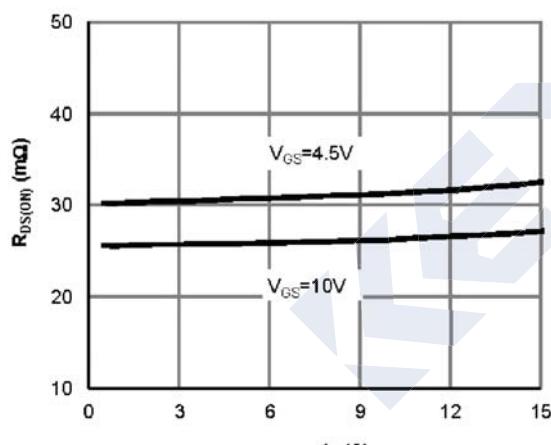


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

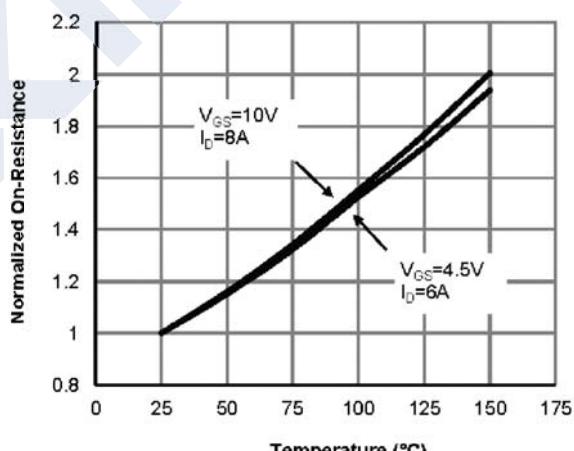


Figure 4: On-Resistance vs. Junction Temperature (Note E)

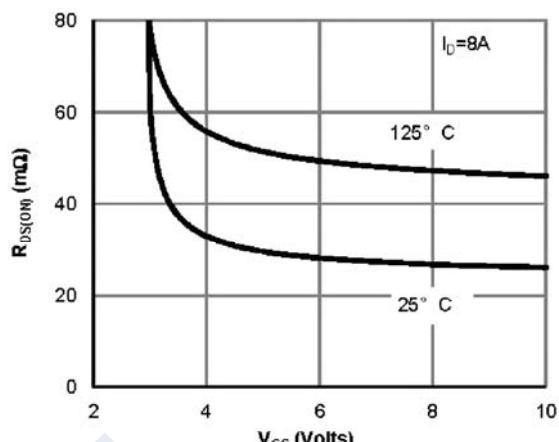


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

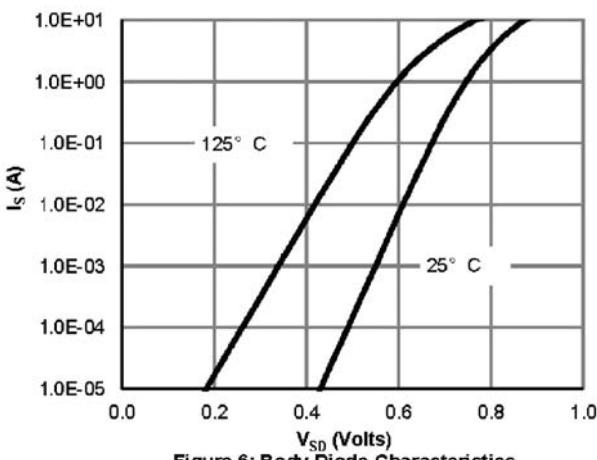


Figure 6: Body-Diode Characteristics (Note E)

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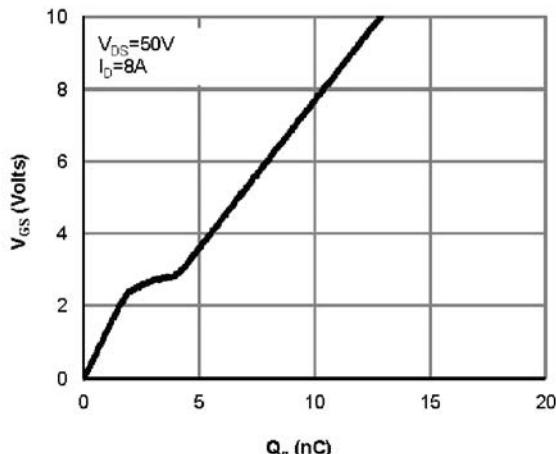


Figure 7: Gate-Charge Characteristics

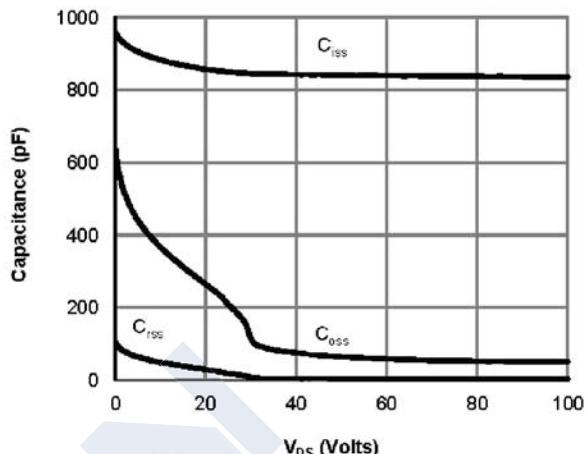


Figure 8: Capacitance Characteristics

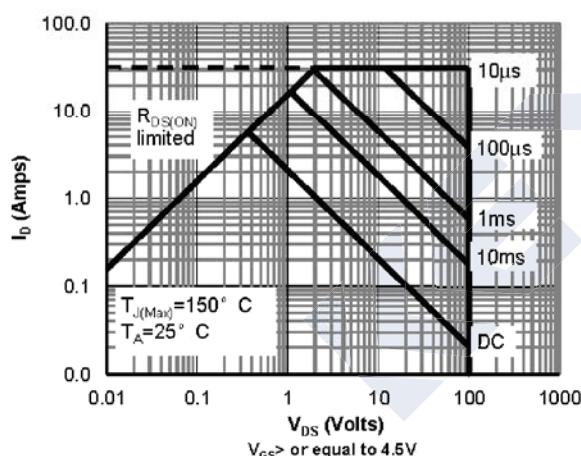


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

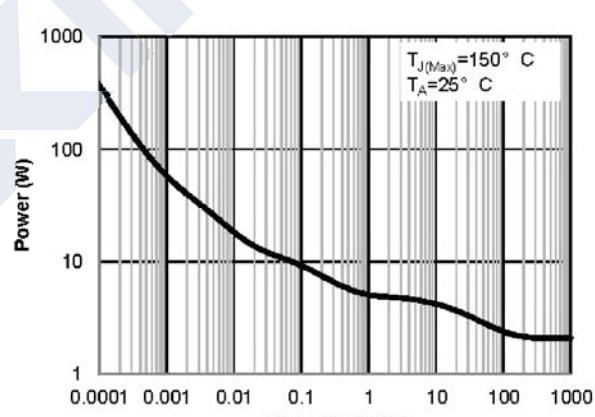


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

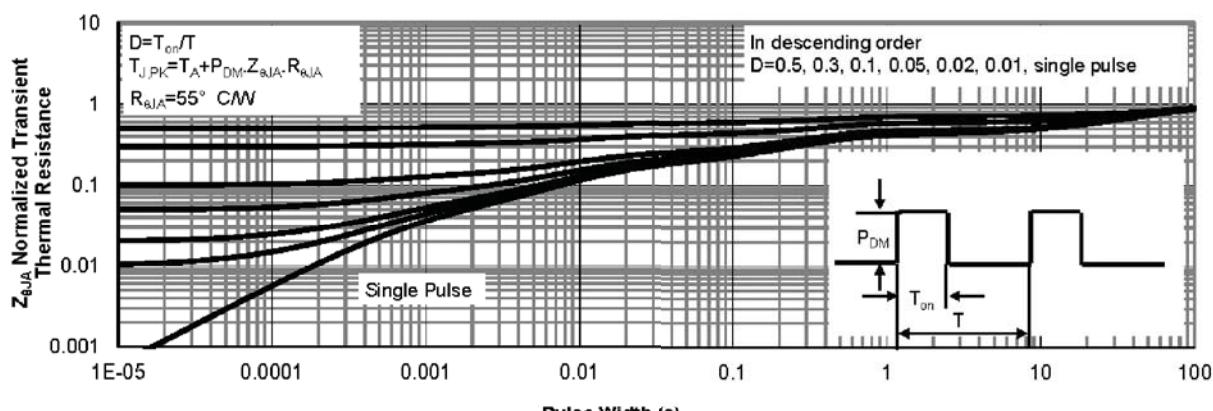


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

N-Channel MOSFET**AON2392 (KON2392)**

Figure A: Gate Charge Test Circuit & Waveforms

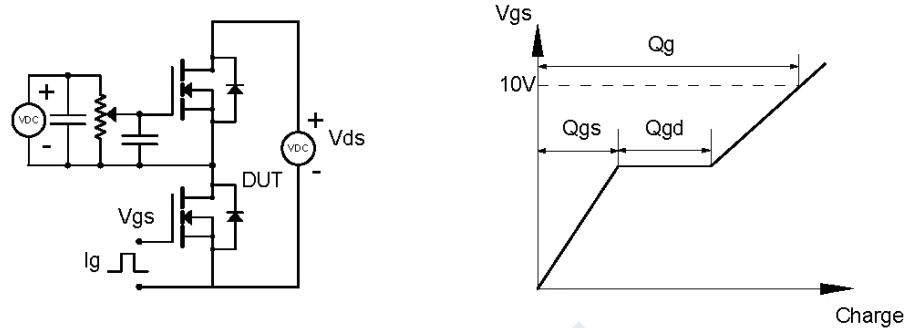


Figure B: Resistive Switching Test Circuit & Waveforms

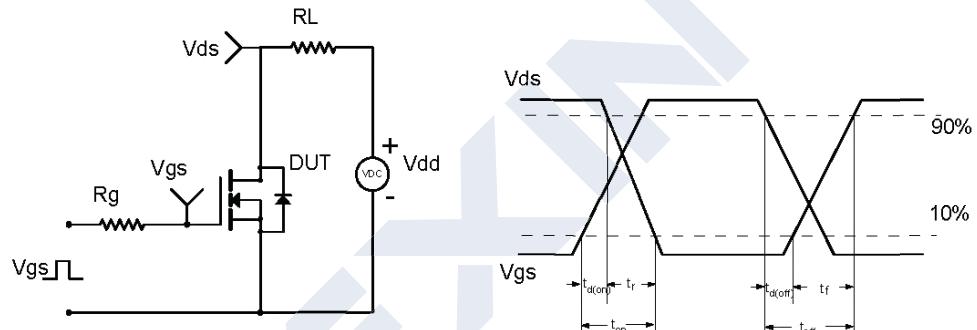


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

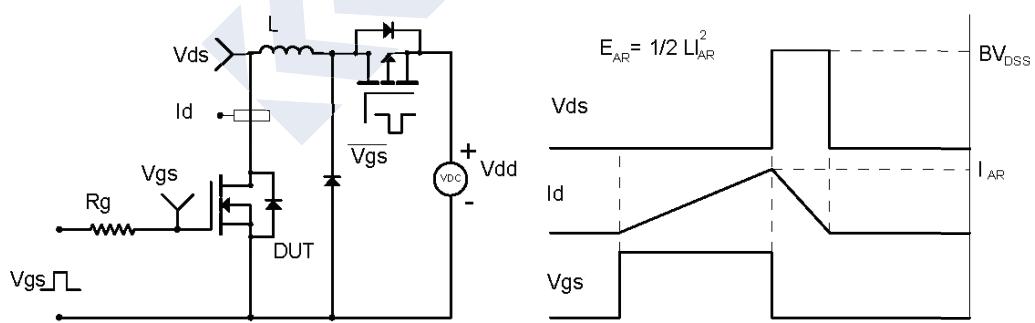


Figure D: Diode Recovery Test Circuit & Waveforms

